

C1206C151K5RACTU

Aliases (C1206C151K5RAC7800) SMD Comm X7R, Ceramic, 150 pF, 10%, 50 VDC, X7R, SMD, MLCC, Temperature Stable, Class II, 1206, 1.5 mm



General Information	
Series	SMD Comm X7R
Style	SMD Chip
Description	SMD, MLCC, Temperature Stable, Class II
Features	Temperature Stable, Class II
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	17 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1206
L	3.2mm +/-0.2mm
W	1.6mm +/-0.2mm
Т	0.78mm +/-0.10mm
S	1.5mm MIN
В	0.5mm +/-0.25mm

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	1.6mm +/-0.2mm	Tolerance	10%
	0.78mm +/-0.10mm	Voltage DC	50 VDC
	1.5mm MIN	Dielectric Withstanding Voltage	125 VDC
	0.5mm +/-0.25mm	Temperature Range	-55/+125°C
		Temp. Coefficient	X7R
ing Specifications		Capacitance Change with	15%, 1kHz 1.0Vrms
ing	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
ing Quantity	4000	Dissipation Factor	2.5%1kHz1.0Vrms

Specification

Specifications	
Capacitance	150 pF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	10%
Voltage DC	50 VDC
Dielectric Withstanding Voltage	125 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	X7R
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	15%, 1kHz 1.0Vrms
Dissipation Factor	2.5% 1 kHz 1.0Vrms
Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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